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January 4, 2007  
Date

**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

Applicants:	Marcus Jacka et al.	Confirmation No.:	6836
Serial No.:	10/518,660		
Filed:	December 17, 2004		
Group Art Unit:	2881		
Examiner:	David A. Vanore		
Title:	Secondary Electron Detector, Especially in a Scanning Electron Microscope		
Attorney Ref. No.:	KANIA-05		

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January 4, 2007

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**COMMENTS ON STATEMENT OF REASONS FOR ALLOWANCE**

Sir:

Applicants' undersigned counsel notes the Examiner's Statement of Reasons for Allowance attached with the Notice of Allowability. The reasons set forth by the Examiner refer only to some of the features in independent claim 1, and are not the only reasons that all of the claims are allowable.

With respect to independent claim 1, the prior art fails to disclose or suggest a secondary electron detector, especially in a scanning electron microscope, comprising: a detector chamber adapted to be coupled with a vacuum pump to produce a vacuum inside the detector chamber, the detector chamber comprising an interior and a plurality of walls separating the

interior from a surrounding environment; at least one source of bias voltage; and a sensor located in said detector chamber and having an active surface, wherein one of said walls of said detector chamber is near to the active surface of the sensor and is closed by an electrically conductive grid, said electrically conductive grid including a plurality of orifices having a high resistance to a transmission of gas and a low resistance to a transmission of electrons, said electrically conductive grid connected with the at least one source of bias voltage, said orifices defining electron microlenses inside and in front of said orifices, said electron microlenses being created by an electrical field protruding through said orifices, said electrical field originating from a conductive coating inside of the detector chamber, and the conductive coating adapted to be connected to a voltage source. Dependent claims 2-9 and 11-14 depend either directly or indirectly from claim 1. Accordingly, each of dependent claims 2-9 and 11-14 is believed to be allowable based upon at least the allowability of independent claim 1 and, furthermore, upon other features set forth in dependent claims 2-9 and 11-14 but not discussed herein.

If the Examiner disagrees with any of these comments, he is respectfully requested to provide further explanation on the record. Applicants do not believe that any fees are due in connection with this submission. However, if such petition is due or any fees are necessary, the Commissioner may consider this to be a request for such and charge any necessary fees to deposit account 23-3000.

Respectfully submitted,  
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